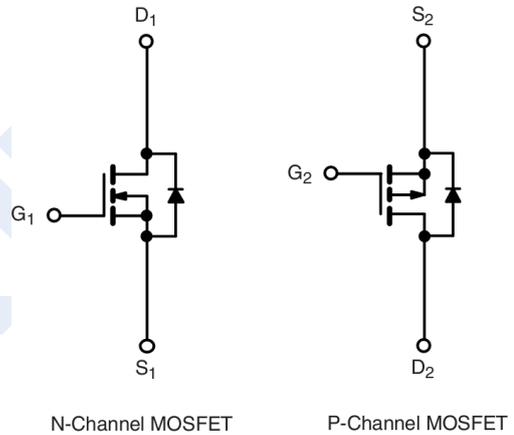
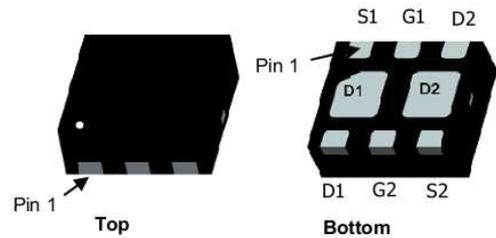


Complementary Enhancement MOSFET

SI5513CD (KI5513CD)

■ Features

- N-Channel: $V_{DS}=20V$ $I_D=4A$ ($V_{GS}=4.5V$)
 - $R_{DS(ON)} < 35m\Omega$ ($V_{GS} = 4.5V$)
 - $R_{DS(ON)} < 50m\Omega$ ($V_{GS} = 2.5V$)
 - $R_{DS(ON)} < 90m\Omega$ ($V_{GS} = 1.8V$)
- P-Channel: $V_{DS}=-20V$ $I_D=-2.5A$ ($V_{GS}=-4.5V$)
 - $R_{DS(ON)} < 85m\Omega$ ($V_{GS} = -4.5V$)
 - $R_{DS(ON)} < 115m\Omega$ ($V_{GS} = -2.5V$)
 - $R_{DS(ON)} < 150m\Omega$ ($V_{GS} = -1.8V$)

■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	N-Channel	P-Channel	Unit
Drain-Source Voltage	V_{DS}	20	-20	V
Gate-Source Voltage	V_{GS}	± 12	± 12	
Continuous Drain Current	I_D	$T_a=25^\circ C$	4	A
		$T_a=70^\circ C$	3.2	
Pulsed Drain Current	I_{DM}	20	-20	
Power Dissipation for Dual Operation	P_D	1.5	1.5	W
Power Dissipation for single Operation $T_a=70^\circ C$		0.95	0.95	
Junction Temperature	T_J	150		$^\circ C$
Storage Temperature Range	T_{stg}	-55 to 150		

Complementary Enhancement MOSFET

SI5513CD (KI5513CD)

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test Conditions	Type	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V _{DSS}	I _D =250 μA, V _{GS} =0V	N-CH	20			V
		I _D =-250 μA, V _{GS} =0V	P-CH	-20			
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V, V _{GS} =0V	N-CH			300	nA
		V _{DS} =-20V, V _{GS} =0V	P-CH			-300	
Gate-Body Leakage Current	I _{GSS}	V _{DS} =0V, V _{GS} =±12V	N-CH			±100	nA
		V _{DS} =0V, V _{GS} =±12V	P-CH			±100	
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250 μA	N-CH	0.62	0.75	1.0	V
		V _{DS} =V _{GS} , I _D =-250 μA	P-CH	-0.5			
Static Drain-Source On-Resistance	R _{DS(on)}	V _{GS} =4.5V, I _D =3.5A	N-CH		25	35	mΩ
		V _{GS} =2.5V, I _D =2.5A			34	50	
		V _{GS} =1.8V, I _D =2A			64	90	
		V _{GS} =-4.5V, I _D =-2.8A	P-CH		80	85	
		V _{GS} =-2.5V, I _D =-2A			95	115	
		V _{GS} =-1.8V, I _D =-2A			117	150	
Forward Transconductance	g _{FS}	V _{DS} =5V, I _D =3A	N-CH		16		S
		V _{DS} =-5V, I _D =-2.5A	P-CH		13		
Input Capacitance	C _{iss}	N-Channel: V _{GS} =8V, V _{DS} =0V, f=1MHz	N-CH		522.3		pF
Output Capacitance	C _{oss}		P-Channel: V _{GS} =0V, V _{DS} =-10V, f=1MHz	P-CH		589	
		Reverse Transfer Capacitance	C _{rss}	N-Channel: V _{GS} =8V, V _{DS} =0V, f=1MHz	N-CH		
P-Channel: V _{GS} =0V, V _{DS} =-10V, f=1MHz	P-CH				91.18		
Total Gate Charge	Q _g	N-Channel: V _{GS} =4.5V, V _{DS} =10V, I _D =4A	N-CH		6.24	8.11	nC
			P-Channel: V _{GS} =-4.5V, V _{DS} =-6V, I _D =-2.5A	P-CH		6.55	
Gate Source Charge	Q _{gs}	N-Channel: V _{GS} =4.5V, V _{DS} =10V, I _D =4A	N-CH		1.64	2.13	
			P-Channel: V _{GS} =-4.5V, V _{DS} =-6V, I _D =-2.5A	P-CH		0.31	
Gate Drain Charge	Q _{gd}	N-Channel: V _{GS} =4.5V, V _{DS} =10V, I _D =4A	N-CH		1.34	1.74	
			P-Channel: V _{GS} =-4.5V, V _{DS} =-6V, I _D =-2.5A	P-CH		1.3	1.69
Turn-On DelayTime	t _{d(on)}	N-Channel: V _{GS} =4.5V, V _{DS} =10V, I _D =1A, R _{GEN} =6Ω	N-CH		10.4	20.8	ns
			P-Channel: V _{GS} =-4.5V, V _{DS} =-6V, I _D =-1A, R _{GEN} =6Ω	P-CH		9.72	
Turn-On Rise Time	t _r	N-Channel: V _{GS} =4.5V, V _{DS} =10V, I _D =1A, R _{GEN} =6Ω	N-CH		4.4	8.8	
			P-Channel: V _{GS} =-4.5V, V _{DS} =-6V, I _D =-1A, R _{GEN} =6Ω	P-CH		3.56	
Turn-Off DelayTime	t _{d(off)}	N-Channel: V _{GS} =4.5V, V _{DS} =10V, I _D =1A, R _{GEN} =6Ω	N-CH		27.38	54.72	
			P-Channel: V _{GS} =-4.5V, V _{DS} =-6V, I _D =-1A, R _{GEN} =6Ω	P-CH		33.32	
Turn-Off Fall Time	t _f	N-Channel: V _{GS} =4.5V, V _{DS} =10V, I _D =1A, R _{GEN} =6Ω	N-CH		4.16	8.32	
			P-Channel: V _{GS} =-4.5V, V _{DS} =-6V, I _D =-1A, R _{GEN} =6Ω	P-CH		4.52	
Maximum Body-Diode Continuous Current	I _S		N-CH			1.7	A
			P-CH			-1.6	
Diode Forward Voltage	V _{SD}	I _S =1.7A, V _{GS} =0V	N-CH		0.74	1.0	V
		I _S =-1.6A, V _{GS} =0V	P-CH	0.6	-0.8	-1.2	

SI5513CD (KI5513CD)

■ N-channel Typical Characteristics

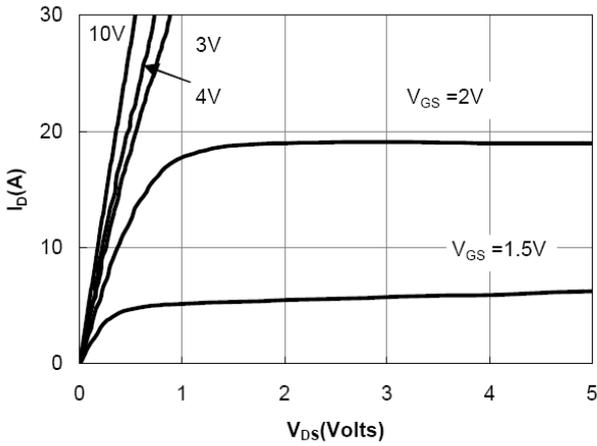


Figure 1: On-Regions Characteristic CS

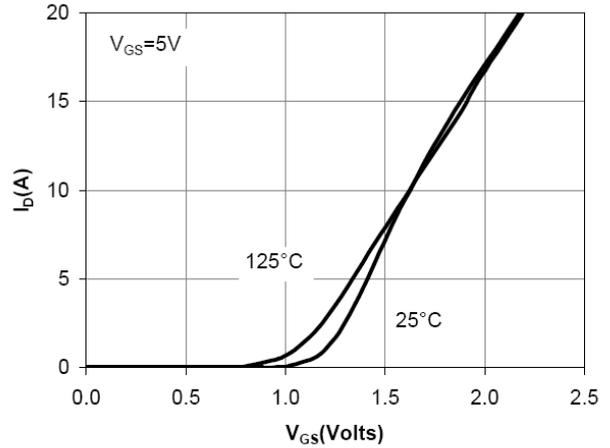


Figure 2: Transfer Characteristics

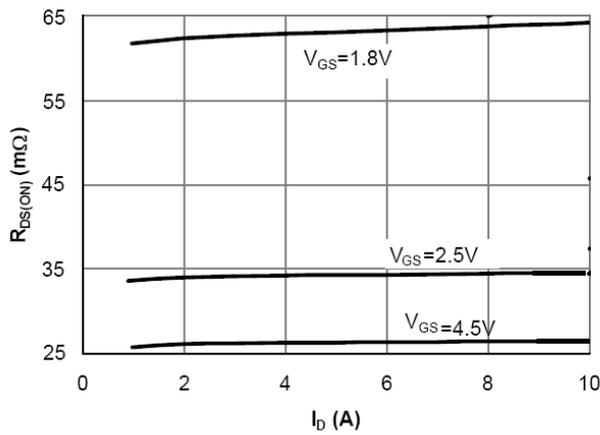


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

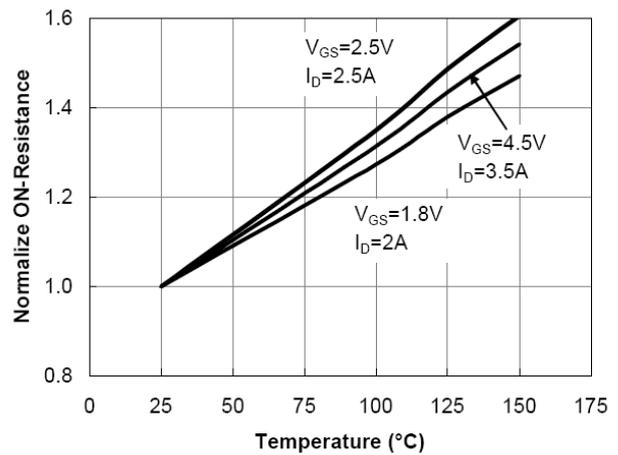


Figure 4: On-Resistance vs. Junction Temperature

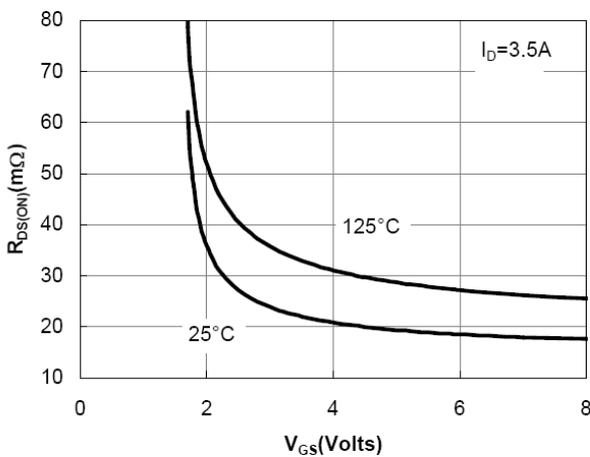


Figure 5: On-Resistance vs. Gate-Source Voltage

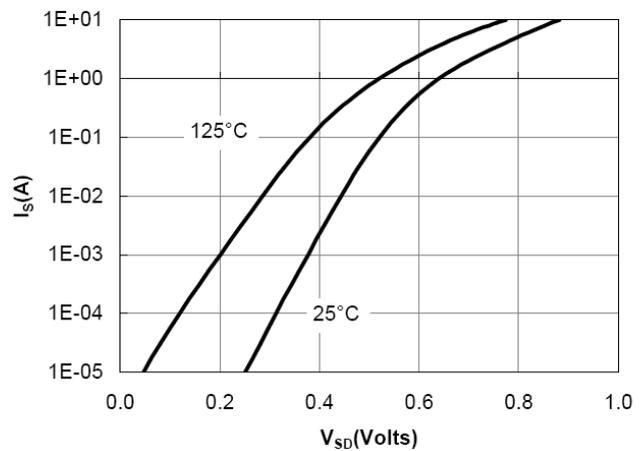


Figure 6: Body-Diode Characteristics

SI5513CD (KI5513CD)

■ N-channel Typical Characteristics

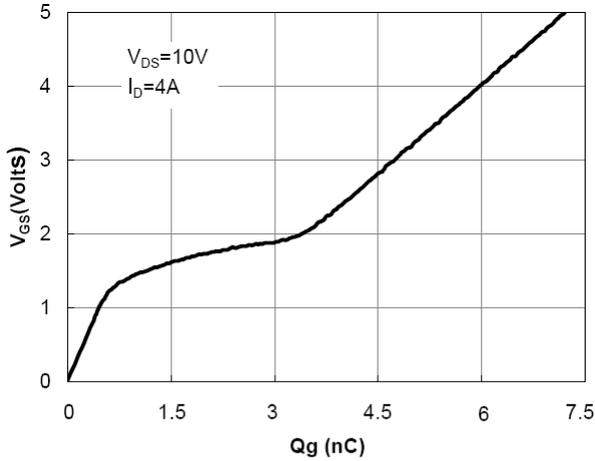


Figure 7: Gate-Charge Characteristics

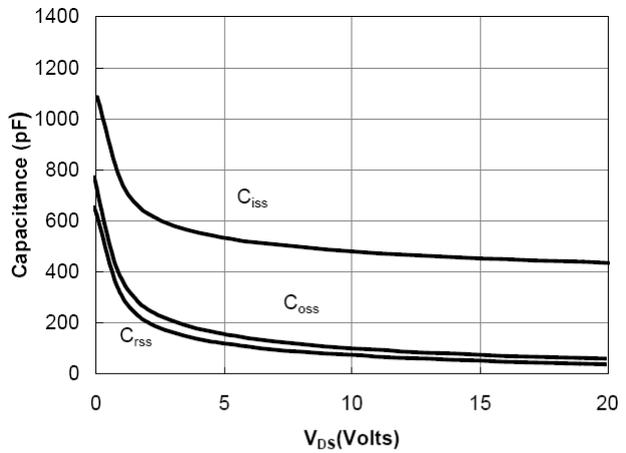


Figure 8: Capacitance Characteristics

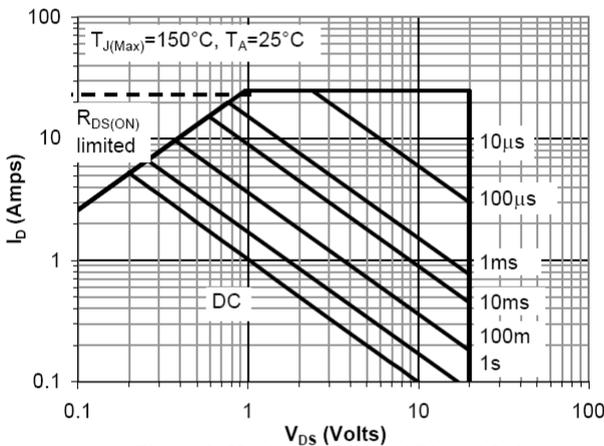


Figure 9: Maximum Forward Biased Safe Operating Area

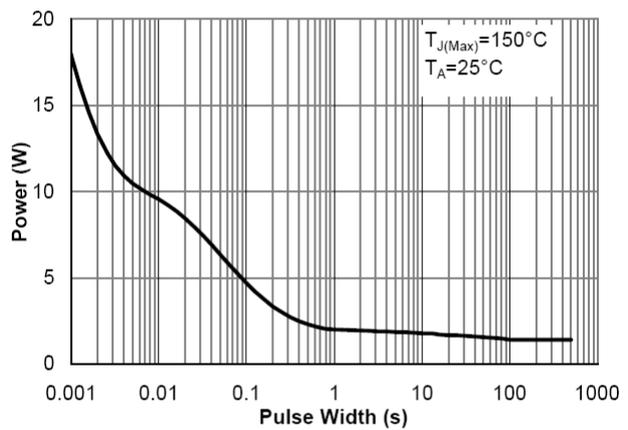


Figure 10: Single Pulse Power Rating Junction-to-Ambient

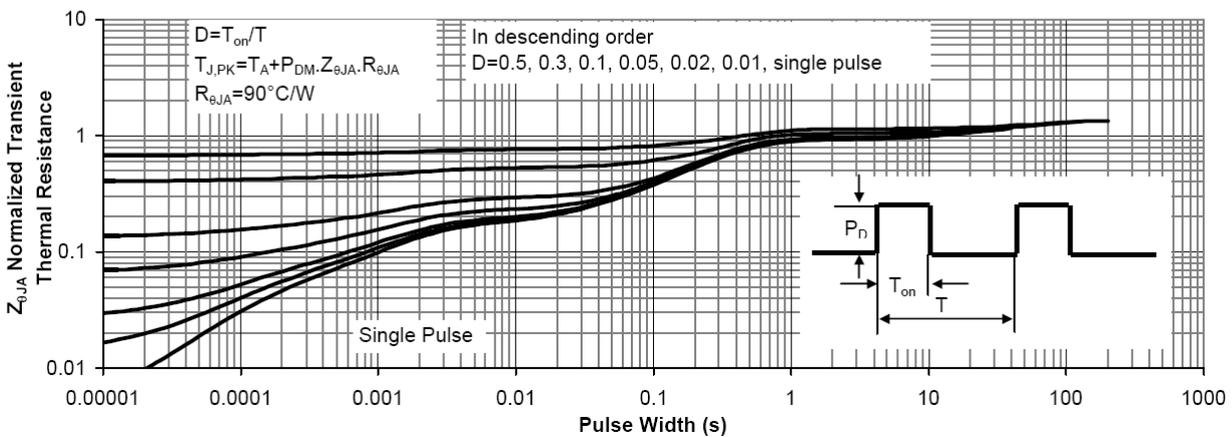


Figure 11: Normalized Maximum Transient Thermal Impedance

SI5513CD (KI5513CD)

■ P-Channel Typical Characteristics

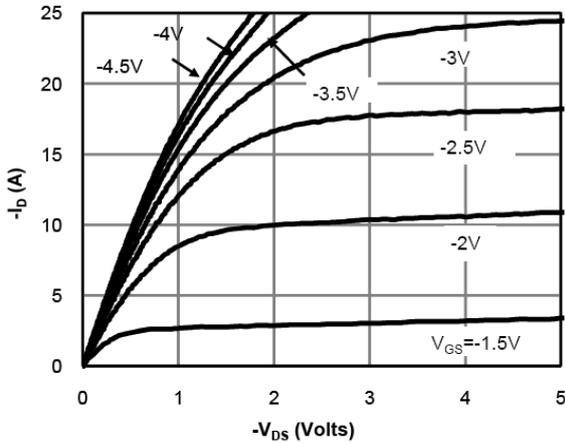


Figure 1: On-Region Characteristics

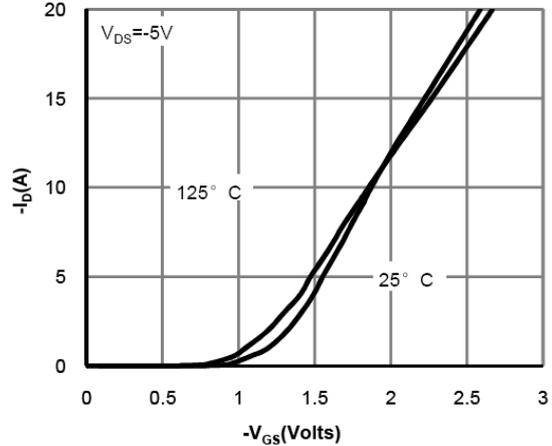


Figure 2: Transfer Characteristics

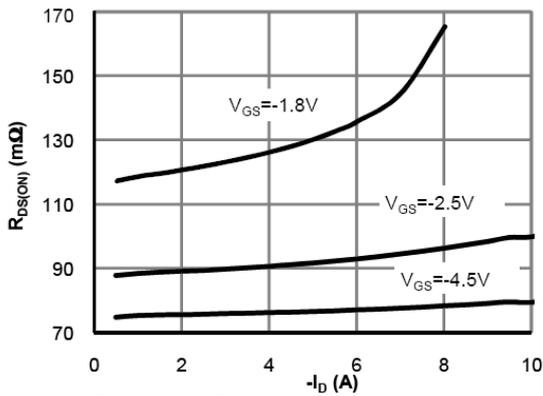


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

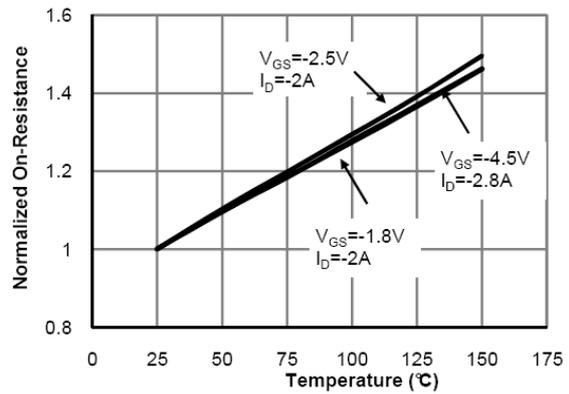


Figure 4: On-Resistance vs. Junction Temperature

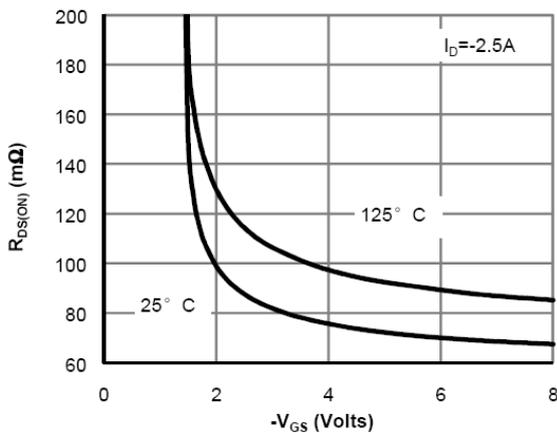


Figure 5: On-Resistance vs. Gate-Source Voltage

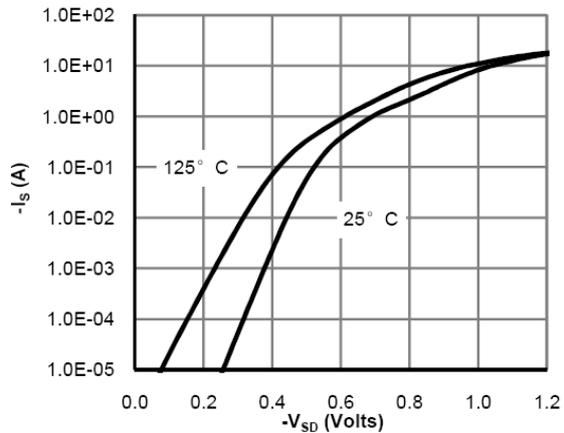


Figure 6: Body-Diode Characteristics

SI5513CD (KI5513CD)

■ P-Channel Typical Characteristics

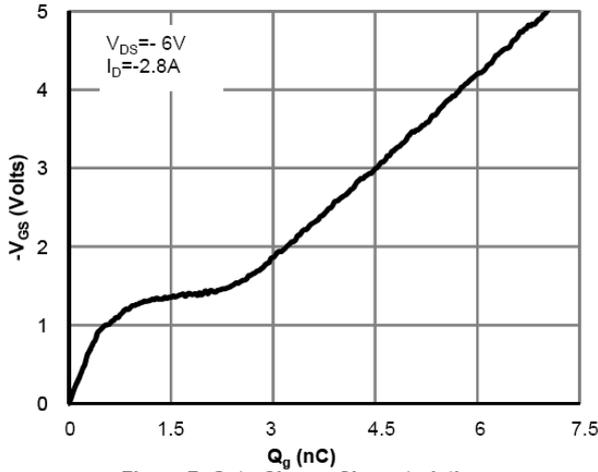


Figure 7: Gate-Charge Characteristics

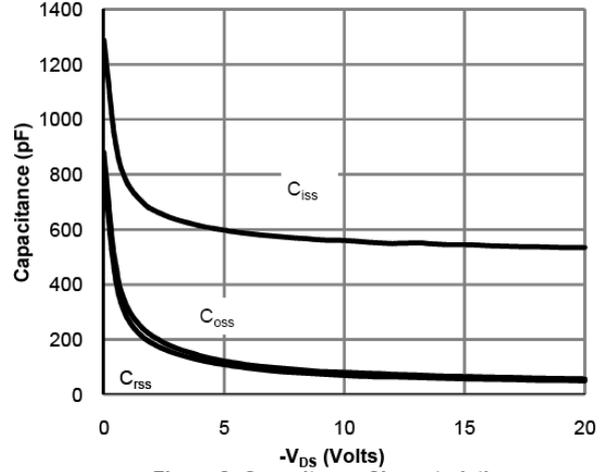


Figure 8: Capacitance Characteristics

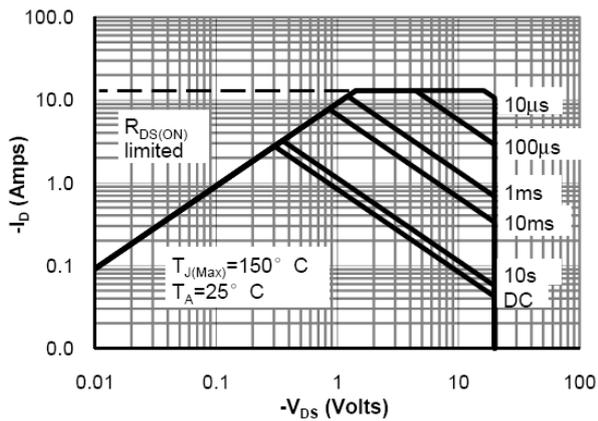


Figure 9: Maximum Forward Biased Safe Operating Area

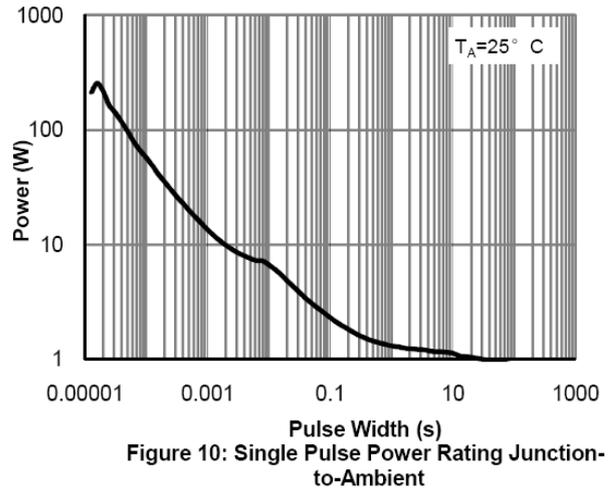


Figure 10: Single Pulse Power Rating Junction-to-Ambient

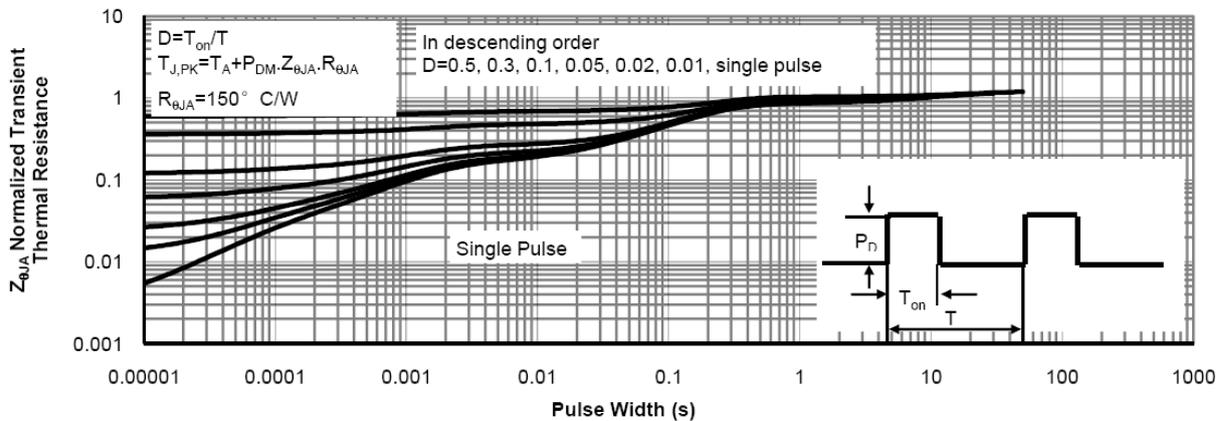


Figure 11: Normalized Maximum Transient Thermal Impedance